Notice of References Cited Evaminer

Application/Control No. 10/574,259	Applicant(s)/Patent Under Reexamination IKEDA ET AL.		
Examiner	Art Unit		
Sun Jae Y. Loewe	1609	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-		•	
	В	US-			
	С	US-			
	D	US-			
	E	US-			, ,
	F	US-			
	G	US-		·	
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q			·		
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Numata et al., CAPLUS AN 2003:117525 (published 2003)			
	V.				
	w				
	x				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.